

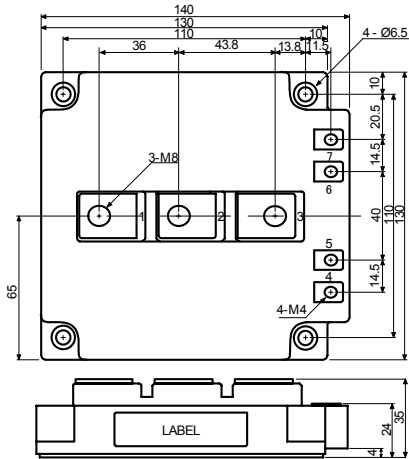
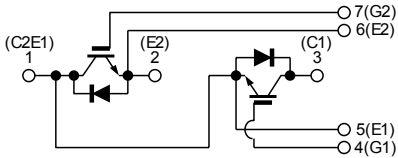
I G B T Module-Dual

6 0 0 A, 1 2 0 0 V

P D M B 6 0 0 B S 1 2

□ 回路図 : *CIRCUIT*

□ 外形寸法図 : *OUTLINE DRAWING*



Dimension: [mm]

□ 最大定格 : *MAXIMUM RATINGS* ($T_c=25^{\circ}\text{C}$)

I t e m		S y m b o l	R a t e d V a l u e		U n i t
コレクタ・エミッタ間電圧 Collector-Emitter Voltage		V _{CES}	1, 200		V
ゲート・エミッタ間電圧 Gate-Emitter Voltage		V _{GES}	±20		V
コレクタ電流 Collector Current	DC	I _C	600		A
	1ms	I _{CP}	1, 200		
コレクタ損失 Collector Power Dissipation		P _C	3, 600		W
接合温度 Junction Temperature Range		T _j	-40~+150		℃
保存温度 Storage Temperature Range		T _{stg}	-40~+125		℃
絶縁耐圧(Terminal to Base AC, 1minute) Isolation Voltage		V _{iso}	2, 500		V _(RMS)
締め付けトルク Mounting Torque	Module Base to Heatsink	F _{tor}	3 (30.6)		N・m (kgf・cm)
	Busbar to Main Terminal		M4	1.4 (14.3)	
			M8	10.5 (107)	

□ 電気的特性 : *ELECTRICAL CHARACTERISTICS* ($T_c=25^{\circ}\text{C}$)

Characteristic		Symbol	Test Condition	Min.	Typ.	Max.	Unit
コレクタ遮断電流 Collector-Emitter Cut-Off Current		I_{CES}	$V_{CE}=1200\text{V}, V_{GE}=0\text{V}$	—	—	6.0	mA
ゲート漏れ電流 Gate-Emitter Leakage Current		I_{GES}	$V_{GE}=\pm 20\text{V}, V_{CE}=0\text{V}$	—	—	1.0	μA
コレクタ・エミッタ間飽和電圧 Collector-Emitter Saturation Voltage		$V_{CE(sat)}$	$I_C=600\text{A}, V_{GE}=15\text{V}$	—	2.3	2.7	V
ゲートしきい値電圧 Gate-Emitter Threshold Voltage		$V_{GE(th)}$	$V_{CE}=5\text{V}, I_C=600\text{mA}$	4.0	—	8.0	V
入力容量 Input Capacitance		C_{ies}	$V_{CE}=10\text{V}, V_{GE}=0\text{V}, f=1\text{MHz}$	—	37,800	—	pF
スイッチング時間 Switching Time	上昇時間 Rise Time	t_r	$V_{CC}=600\text{V}$ $R_L=1.0\Omega$ $R_G=2.7\Omega$ $V_{GE}=\pm 15\text{V}$	—	0.25	0.45	μs
	ターンオン時間 Turn-on Time	t_{on}		—	0.40	0.70	
	下降時間 Fall Time	t_f		—	0.25	0.35	
	ターンオフ時間 Turn-off Time	t_{off}		—	0.80	1.10	

□ フリーホイーリングダイオードの特性 : *FREE WHEELING DIODE RATINGS & CHARACTERISTICS* ($T_c=25^{\circ}\text{C}$)

I t e m		S y m b o l	R a t e d V a l u e		U n i t
順電流 Forward Current	DC	I_{F}	400		A
	1 m s	I_{FM}	800		

Characteristic		Symbol	Test Condition	Min.	Typ.	Max.	Unit
順電圧 Peak Forward Voltage		V_F	$I_F=600\text{A}, V_{GE}=0\text{V}$	—	2.2	2.6	V
逆回復時間 Reverse Recovery Time		t_{rr}	$I_F=600\text{A}, V_{GE}=-10\text{V}$ $di/dt=1200\text{A}/\mu\text{s}$	—	0.2	0.3	μs

□ 熱的特性 : *THERMAL CHARACTERISTICS*

Characteristic		Symbol	Test Condition	Min.	Typ.	Max.	Unit
熱抵抗 Thermal Impedance	IGBT	$R_{th(j-c)}$	Junction to Case	—	—	0.035	$^{\circ}\text{C}/\text{W}$
	Diode			—	—	0.071	

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Fig.1- Output Characteristics (Typical)

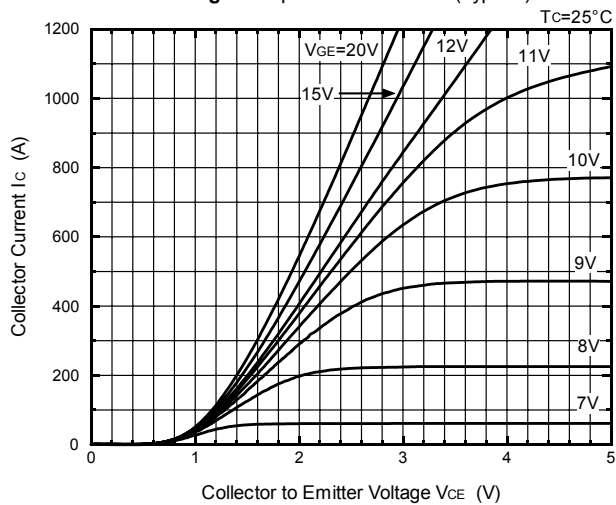


Fig.2- Output Characteristics (Typical)

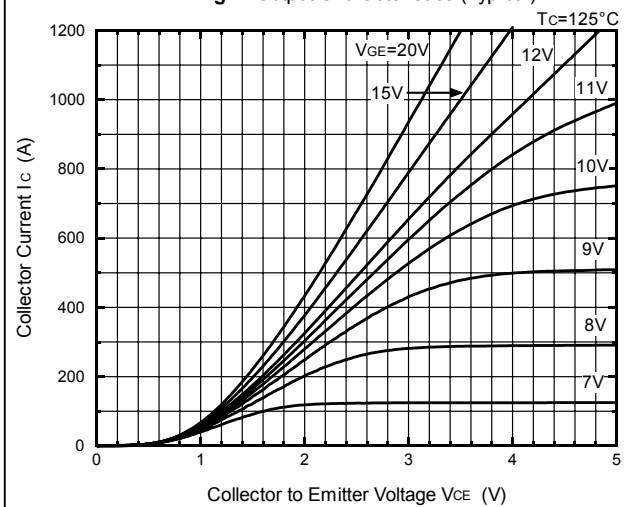


Fig.3- Collector to Emitter On Voltage vs. Gate to Emitter Voltage (Typical)

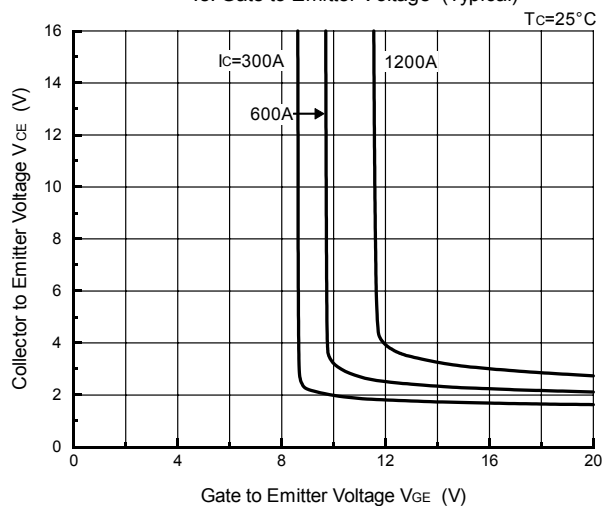


Fig.4- Collector to Emitter On Voltage vs. Gate to Emitter Voltage (Typical)

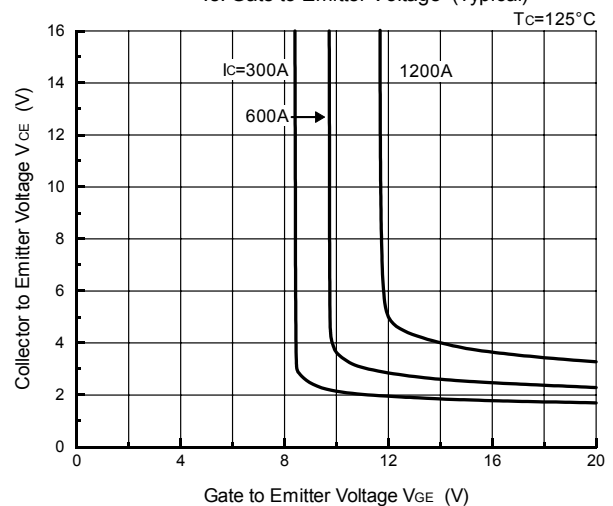


Fig.5- Gate Charge vs. Collector to Emitter Voltage (Typical)

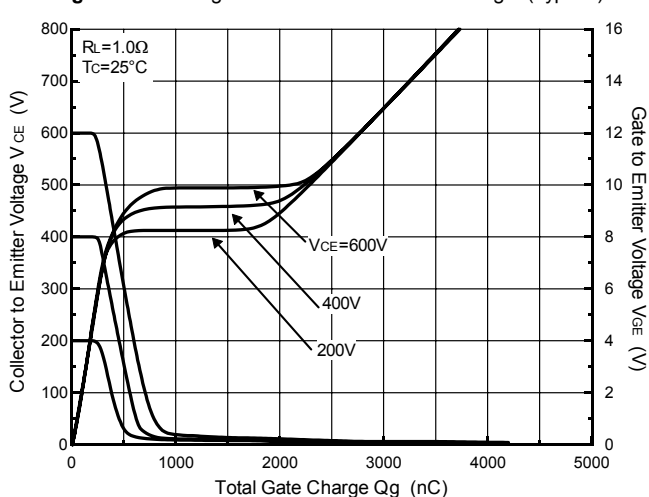
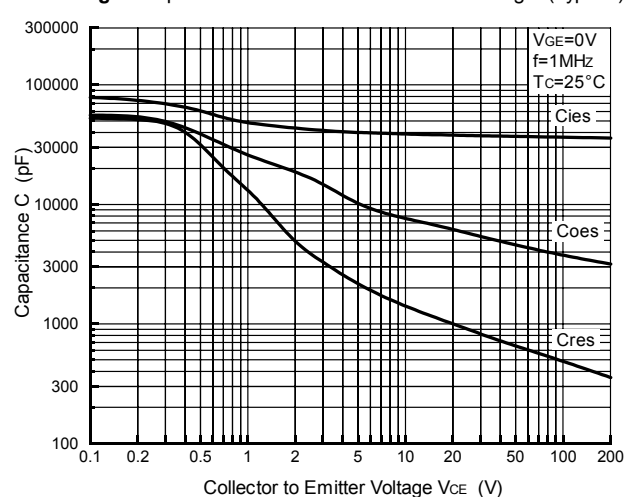


Fig.6- Capacitance vs. Collector to Emitter Voltage (Typical)



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Fig.7- Collector Current vs. Switching Time (Typical)

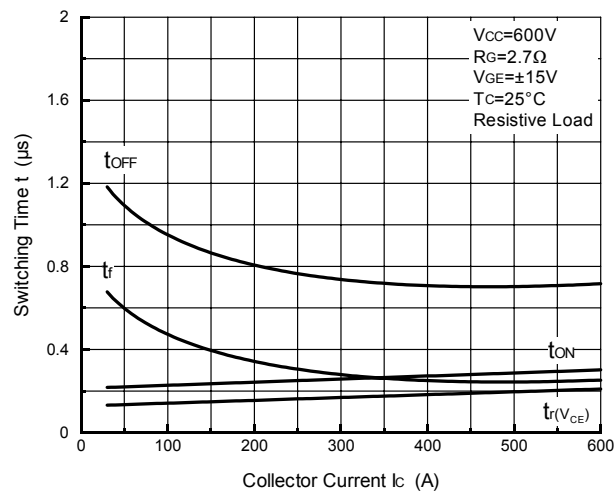


Fig.8- Series Gate Impedance vs. Switching Time (Typical)

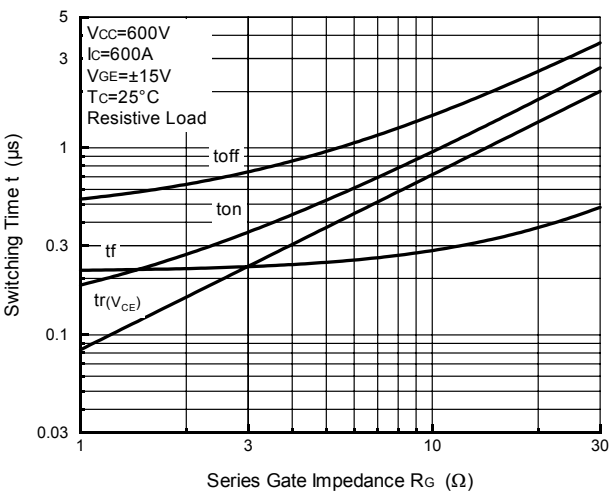


Fig.9- Collector Current vs. Switching Time

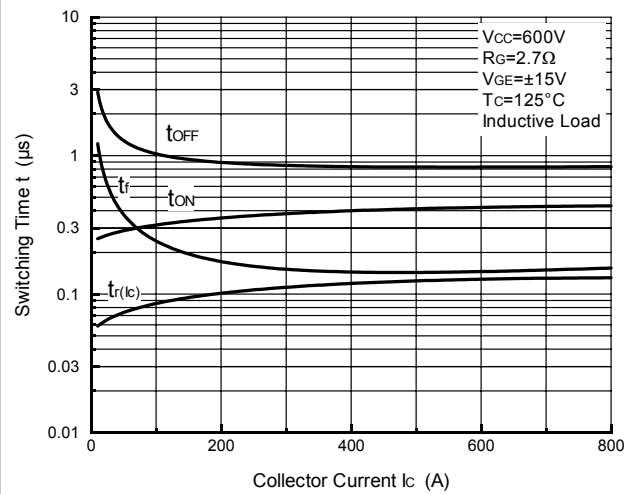


Fig.10- Series Gate Impedance vs. Switching Time

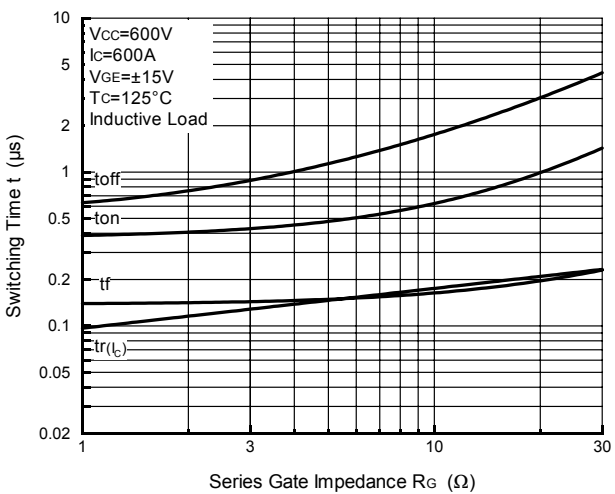


Fig.11- Collector Current vs. Switching Loss

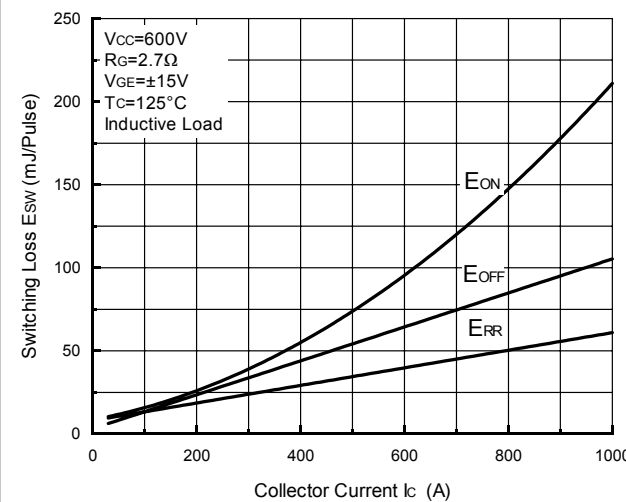
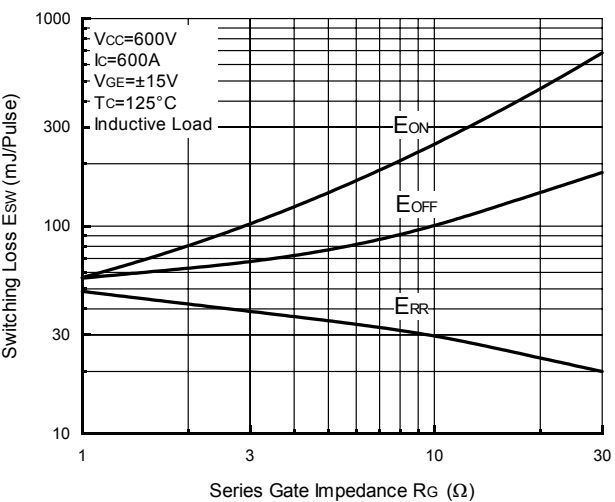


Fig.12- Series Gate Impedance vs. Switching Loss



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Fig.13- Forward Characteristics of Free Wheeling Diode (Typical)

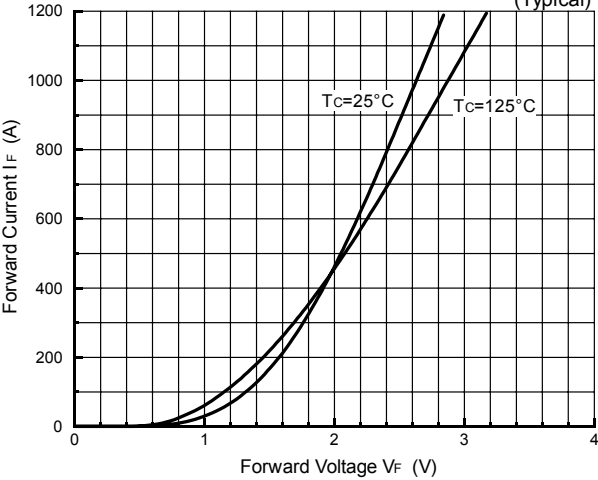


Fig.14- Reverse Recovery Characteristics (Typical)

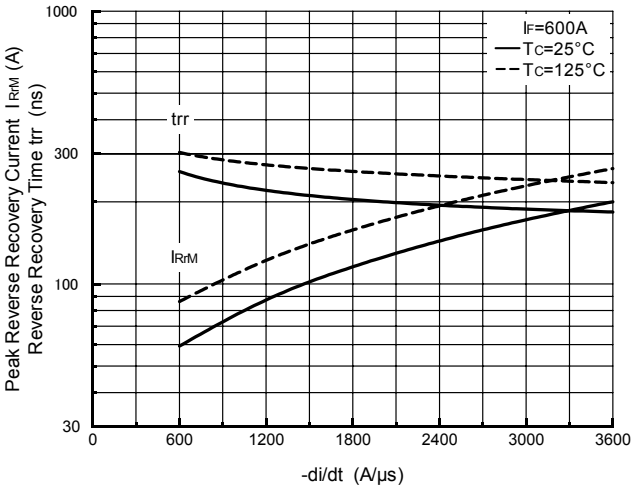


Fig.15- Reverse Bias Safe Operating Area

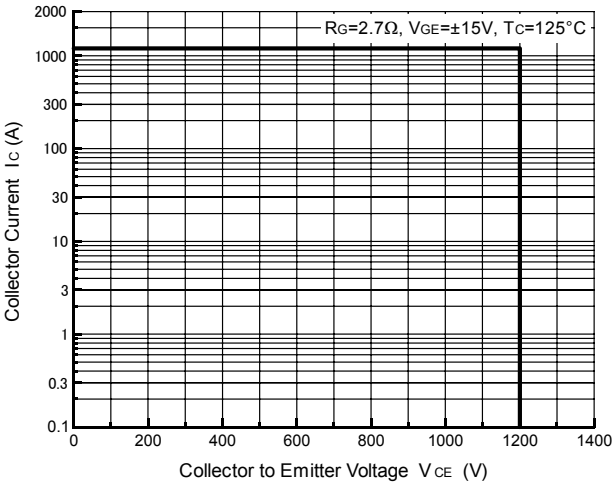


Fig.16- Transient Thermal Impedance

